Claims:

1. A method of analysis of a sample, the method comprising:

providing a sample holder having an upper surface and a lower surface, the upper surface having a plasmonic layer associated therewith, the plasmonic layer including a periodic array of sub-micron structures;

applying the sample to the upper surface of the sample holder;

illuminating the sample with light so that said light interacts with the sample and sample holder;

forming an image using said light, after interaction with said sample and sample holder, wherein at least one localised structural property of the sample is visible in the image based on a colour of the received light; and

using the image formed to control a subsequent analysis process.

2. The method of claim 1, wherein using the image formed to control a subsequent analysis process includes any one or more of the following:

defining one or more datum points or a coordinate system used in the subsequent analysis,

selecting a region of a sample for further analysis; and

determining an order or schedule for said subsequent analysis.

3. A method of selecting a region of interest of a sample, for use in a subsequent analysis process, the method including:

providing a sample holder having an upper surface face and a lower surface, the upper surface having a plasmonic layer associated therewith, the plasmonic layer including a periodic array of sub-micron structures;

applying a sample, in which the region of interest is to be determined, to the upper surface of the sample holder;

illuminating the sample with light so that said light interacts with the sample and sample holder;

forming an image using said light, after interaction with said sample and sample holder, wherein at least one localised structural property of the sample is visible in the image based on the colour of received light; and

selecting a region of interest of said sample applied to the sample holder at least partly on the basis of a colour of at least part of the sample.

4. The method of claim 3, wherein the method further includes, performing a subsequent analysis on a subsequent-analysis sample corresponding to the selected region of interest.

5 The method of claim 3, wherein selecting the region of interest of the sample includes sectioning a portion of the sample including selected region of interest to create the subsequent-analysis sample corresponding to the selected region of interest.

6. The method as claimed in claim 1, wherein the sample is used as the subsequent-analysis sample.

7. The method as claimed in claim 1, wherein the subsequent analysis process is a subsequent imaging process.

8. The method as claimed in claim 1, including one or more of:

determining an order or schedule for said subsequent analysis;

performing the subsequent analysis on a region of interest;

only performing the subsequent analysis on a region of interest;

performing the subsequent analysis on a region of interest before other regions not being a region of interest; and

transferring one or more datum points or a coordinate system from the sample for use in the subsequent analysis.

9. The method as claimed in claim 1, wherein the localised structural property is a dielectric constant of the sample at a location.

10. A system for forming an image using a method as claimed in claim 1.

11. A system as claimed in claim 10, including a microscope having an image forming system, an illumination system and a sample holder having an upper surface and a lower surface, the upper surface having a plasmonic layer associated therewith, the plasmonic layer including a periodic array of sub-micron structures.

12. A system as claimed in claim 11, including an image capture system to generate a digital image of the sample.

13. A system as claimed in claim 10, including a system for a subsequent analysis.

14. The system as claimed in claim 13, wherein the system for subsequent analysis includes any one or more of the following:

an optical microscope;

an electron microscope;

a scanning probe microscope;

an X-ray microscope;

a transmission electron microscope (TEM).

15. The method as claimed in claim 3, wherein the sample is used as the subsequent-analysis sample.

16. The method as claimed in claim 3, wherein the subsequent analysis process is a subsequent imaging process or a subsequent microscopy process.

17. The method as claimed in claim 3, including one or more of:

determining an order or schedule for said subsequent analysis;

performing the subsequent analysis on a region of interest;

only performing the subsequent analysis on a region of interest;

performing the subsequent analysis on a region of interest before other regions not being a region of interest; and

transferring one or more datum points or a coordinate system from the sample for use in the subsequent analysis.

18. The method as claimed in claim 3, wherein the localised structural property is a dielectric constant of the sample at a location.

19. A system for forming an image using a method as claimed in claim 3.

20. A system as claimed in claim 19, including a microscope having an image forming system, an illumination system and a system configured to control the subsequent analysis process on the basis of the image formed, for use with a sample holder having an upper surface and a lower surface, the upper surface having a plasmonic layer associated therewith, the plasmonic layer including a periodic array of sub-micron structures.

21. A system as claimed in claim 20, including an image capture system to generate a digital image of the sample.

22. A system as claimed in claim 19, including a system for a subsequent analysis.

23. The system as claimed in claim 22, wherein the system for subsequent analysis includes any one or more of the following:

an optical microscope;

an electron microscope;

a scanning probe microscope;

an X-ray microscope;

a transmission electron microscope (TEM).